

## Supplementary Information

### **KMnCuTe<sub>2</sub>: a layered antiferromagnetic semiconductor with long metal-metal distance**

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Table S1. Crystal data and structure refinement for KMnCuTe<sub>2</sub> at 293 K.

Empirical formula	KMn <sub>1.04</sub> Cu <sub>0.96</sub> Te <sub>2</sub>
Formula weight	412.52
Temperature	293(2) K
Wavelength	0.71073 Å
Crystal system	tetragonal
Space group	<i>I4/mmm</i>
Unit cell dimensions	$a = 4.3115(3)$ Å $c = 14.9360(20)$ Å
Volume	277.64(10) Å <sup>3</sup>
Z	2
Density (calculated)	4.935 g/cm <sup>3</sup>
Absorption coefficient	16.932 mm <sup>-1</sup>
F(000)	354
Crystal size	0.4 × 0.3 × 0.05 mm <sup>3</sup>
θ range for data collection	2.73 to 27.95°
Index ranges	-5 ≤ h ≤ 5, -5 ≤ k ≤ 5, -19 ≤ l ≤ 19
Reflections collected	1097
Independent reflections	130 [R <sub>int</sub> = 0.0389]
Completeness to θ = 25.242°	99%
Refinement method	Full-matrix least-squares on F <sup>2</sup>
Data / restraints / parameters	130 / 0 / 9
Goodness-of-fit	1.57
Final R indices [I > 2σ(I)]	R <sub>obs</sub> = 0.0202, wR <sub>obs</sub> = 0.0477
R indices [all data]	R <sub>all</sub> = 0.0206, wR <sub>all</sub> = 0.0478
Largest diff. peak and hole	1.15 and -0.46 e·Å <sup>-3</sup>

$$R = \frac{\sum ||F_o| - |F_c||}{\sum |F_o|}, wR = \left\{ \frac{\sum [w(|F_o|^2 - |F_c|^2)^2]}{\sum [w(|F_o|^4)]} \right\}^{1/2} \text{ and } w = 1 / [\sigma^2(F_o^2) + (0.0317P)^2] \text{ where } P = (F_o^2 + 2F_c^2) / 3$$

Table S2. Atomic coordinates ( $\times 10^4$ ) and equivalent isotropic displacement parameters

( $\text{\AA}^2 \times 10^3$ ) for  $\text{KMnCuTe}_2$  at 293 K with estimated standard deviations in parentheses.

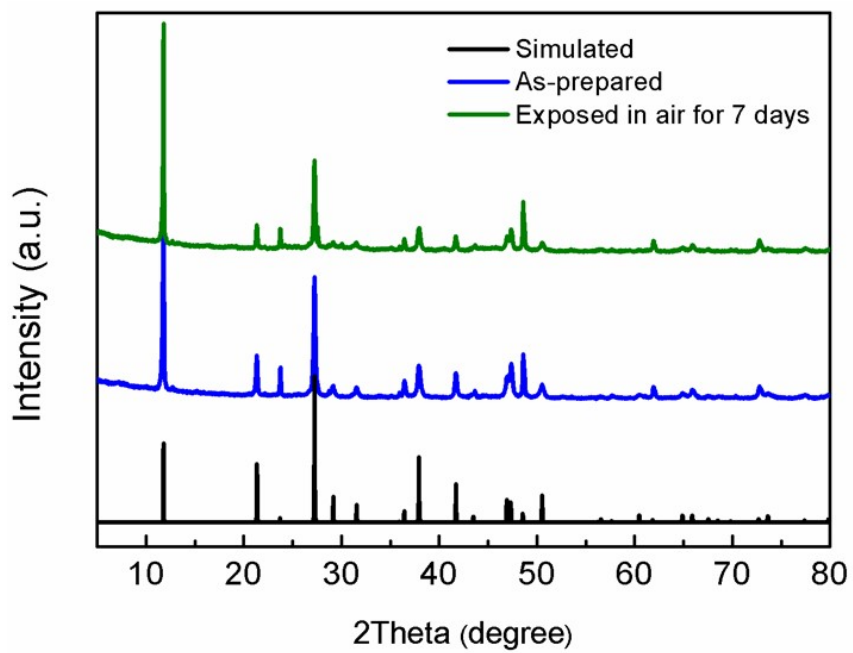
Label	x	y	z	Occupancy	$U_{\text{eq}}^*$
K(1)	0	0	0	1	33(1)
Te(1)	0	0	3605(1)	1	19(1)
Mn(1)	0	5000	2500	0.52(3)	25(1)
Cu(1)	0	5000	2500	0.48(3)	25(1)

\* $U_{\text{eq}}$  is defined as one third of the trace of the orthogonalized  $U_{ij}$  tensor.

Table S3. Anisotropic displacement parameters ( $\text{\AA}^2 \times 10^3$ ) for  $\text{KMnCuTe}_2$  at 293 K with estimated standard deviations in parentheses.

Label	$U_{11}$	$U_{22}$	$U_{33}$	$U_{12}$	$U_{13}$	$U_{23}$
K(1)	30(2)	30(2)	38(2)	0	0	0
Te(1)	19(1)	19(1)	20(1)	0	0	0
Mn(1)	23(1)	23(1)	30(1)	0	0	0
Cu(1)	23(1)	23(1)	30(1)	0	0	0

The anisotropic displacement factor exponent takes the form:  $-2\pi^2[h^2a^*U_{11} + \dots + 2hka^*b^*U_{12}]$ .



**Fig. S1** PXRD patterns of the  $\text{KMnCuTe}_2$  powder sample compared with the simulated one from SCXRD.